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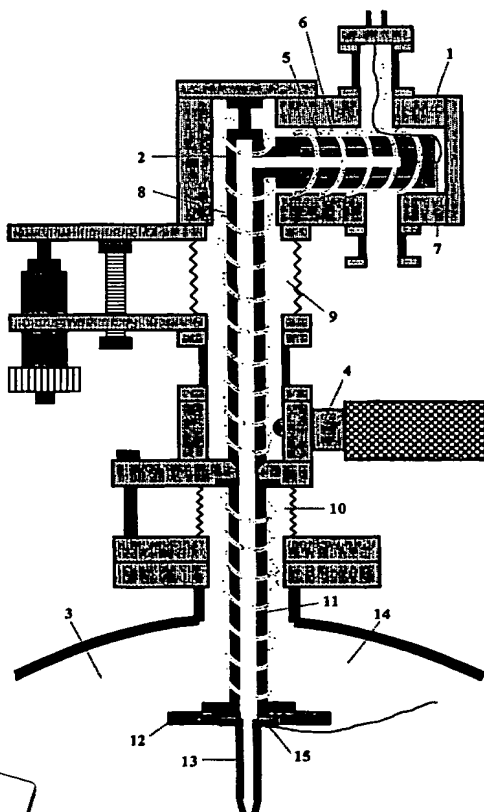
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[Continued on next page]

(54) Title: **METHOD AND APPARATUS FOR IN SITU DEPOSITING OF NEUTRAL CS UNDER ULTRA-HIGH VACUUM TO ANALYTICAL ENDS**



(57) Abstract: The present invention relates to a method for modifying the electronic properties of a surface to analytical ends, such as SIMS or electron spectroscopy, characterised in that it comprises in situ deposition of pure neutral cesium (Cs^0), under ultra-high vacuum, said neutral cesium being enabled in the form of a collimated adjustable stream. The invention relates also to the special column designed for implementing the method and to the corresponding energy and/or mass analyser instrument.

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ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PT, RO,
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INTERNATIONAL SEARCH REPORT

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According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

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Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	T. WIRTZ, B. DUEZ, H. -N. MIGEON, H. SCHERRER: "Useful yields of MCs+ and MCs2+ clusters: a comparative study between the Cameca IMS 4f and the Cation Mass Spectrometer" INTERNATIONAL JOURNAL OF MASS SPECTROMETRY, vol. 209, 2001, pages 57-67, XP001197305 cited in the application	1,3,4, 8-12,14, 15,17,18
Y	page 58, left-hand column, line 19 - right-hand column, line 22 page 66, right-hand column, last paragraph; figure 1 ----- -/-	2,5-7,16

☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
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